

Search Notes

Application/Control No.

10/627,677

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under
Reexamination

IMACHI ET AL.

Art Unit

1745

SEARCHED

Class	Subclass	Date	Examiner
429	129	6/6/2006	DWY
429	218.1	6/6/2006	DWY
429	231.8	6/6/2006	DWY
429	231.95	6/6/2006	DWY

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	6/6/2006	DWY